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# **National Institute of Standards and Technology**



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National Institute of Standards and Technology

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- Analytical Chemistry
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- Time and Frequency<sup>1</sup>
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- Information Access and User Interfaces
- High Performance Systems and Services
- Distributed Computing and Information Services
- Software Diagnostics and Conformance Testing
- Statistical Engineering

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<sup>1</sup> At Boulder, CO 80303.

<sup>2</sup> Some elements at Boulder, CO.

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